U.S. DEPARTMENT OF COMMERCE ATTY, DOCKET NO. Form F SERIAL NO. PATENT AND TRADEMARK OFFICE MI22-2331 10/618,471 LIST OF ART CITED BY APPLICANT APPLICANT: Luan C. Tran (Use several sheets if necessary) **FILING DATE GROUP** July 11, 2003 2813 **U.S. PATENT DOCUMENTS** \*Examiner's Subclass Filing Date Document Date Name Class Initials If Appropriate 6,054,730 04/2000 Noguchi 257 306 6,466,489 10/2002 leong et al. 365 189.09 AB 6,579,751 06/2003 438 6,200,863 03/2001 Xiang et al. 438 286 AD 6,238,967 05/2001 Shiho et al. 438 244 Æ 6,620,679 09/2003 Tzeng et al. 438 250 AF 6,008,080 12/1999 Chuang et al. 438 200 5.834,851 11/1998 Ikeda et al. 257 903 Hayden et al. 5,371,026 12/1994 437 41 A 2003/0205745 11/2003 257 296 Nam FOREIGN PATENT DOCUMENTS Translation Date Country Class Number Νo Yes OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) S. J. Ahn et al., "Novel DRAM Cell Transistor with Asymmetric Source and Drain Junction Profiles Improving Data Retention Characteristics" IEEE, 2002, pp. 176-177. -Schirm DATE CONSIDERED EXAMINER \*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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XX	AB	4,785	5,342	11/15/88	YAMANARA ET AL.		357	51				
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XIL	AD	6,074	1,924	06/13/00	DENNISON ET AL.		438	306				
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XX	¥В	5,736,444	4/07/1998	KAUFFMAN ET AL.	<del></del>	438	257		
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